

July 2009

## **FDMC8678S**

# N-Channel Power Trench<sup>®</sup> SyncFET<sup>TM</sup> 30V, 18A, 5.2m $\Omega$

#### **Features**

- Max  $r_{DS(on)} = 5.2m\Omega$  at  $V_{GS} = 10V$ ,  $I_D = 15A$
- Max  $r_{DS(on)} = 8.7 \text{m}\Omega$  at  $V_{GS} = 4.5 \text{V}$ ,  $I_D = 12 \text{A}$
- Advanced Package and Silicon combination for low r<sub>DS(on)</sub> and high efficiency
- SyncFET Schottky Body Diode
- MSL1 robust package design
- RoHS Compliant



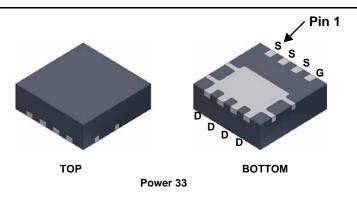
#### **General Description**

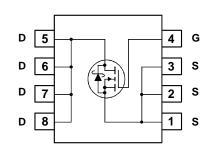
The FDMC8678S has been designed to minimize losses in power conversion applications. Advancements in both silicon and package technologies have been combined to offer the lowest  $r_{DS(on)}$  while maintaining excellent switching performance. This device has the added benefit of an efficient monolithic Schottky body diode.

## **Applications**

Synchronous Rectifier for DC/DC Converters

- Notebook Vcore/ GPU low side switch
- Networking Point of Load low side switch
- Telecom secondary side rectification





## **MOSFET Maximum Ratings** T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter	Parameter			Units
$V_{DS}$	Drain to Source Voltage			30	V
$V_{GS}$	Gate to Source Voltage			±20	V
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25°C		18	
I <sub>D</sub>	-Continuous (Silicon limited)	T <sub>C</sub> = 25°C		66	Δ.
	-Continuous	T <sub>A</sub> = 25°C	(Note 1a)	15	Α
	-Pulsed			60	
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	181	mJ
D	Power Dissipation			41	W
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1a)	2.3	VV
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature R	ange		-55 to +150	°C

## **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1)	53	C/VV

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
8678S	FDMC8678S	Power 33	13"	12 mm	3000 units

## **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 1 \text{mA}, V_{GS} = 0 \text{V}$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1mA, referenced to 25°C		38		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	$V_{GS} = 0V, V_{DS} = 24V,$			500	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$			±100	nA

#### **On Characteristics**

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 1mA$	1	1.9	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 1mA, referenced to 25°C		-3.7		mV/°C
		$V_{GS} = 10V, I_D = 15A$		4.3	5.2	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 4.5V, I_D = 12A$		6.3	8.7	mΩ
		$V_{GS} = 10V, I_D = 15A, T_J = 125$ °C		6	10	
9 <sub>FS</sub>	Forward Transconductance	$V_{DD} = 10V, I_D = 15A$		55		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 45V V 0V	1560	2075	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 15V, V_{GS} = 0V,$ $f = 1MHz$	810	1080	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1101112	90	135	pF
$R_g$	Gate Resistance	f = 1MHz	0.8		Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time	., .=., .	11	20	ns
t <sub>r</sub>	Rise Time	$V_{DD} = 15V, I_{D} = 15A,$ $V_{GS} = 10V, R_{GEN} = 6\Omega$	3	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = 10V, K <sub>GEN</sub> = 012	24	39	ns
t <sub>f</sub>	Fall Time		2	10	ns
$Q_g$	Total Gate Charge	V <sub>GS</sub> =0Vto10V	24	34	nC
Qg	Total Gate Charge	$V_{GS} = 0V \text{ to } 4.5V  V_{DD} = 15V,$	11	16	nC
Q <sub>gs</sub>	Gate to Source Charge	I <sub>D</sub> = 15A	4.7		nC
Q <sub>gd</sub>	Gate to Drain "Miller" Charge		2.8		nC

## **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_{S} = 3A$	(Note 2)	0.5	0.7	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 15A, di/dt = 300A/μs		31	51	ns
Q <sub>rr</sub>	Reverse Recovery Charge	1F = 15A, αι/αι = 300A/μS		33	51	nC

#### NOTES

1.  $R_{BJA}$  is determined with the device mounted on a 1in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material.  $R_{BJC}$  is guaranteed by design while  $R_{BCA}$  is determined by the user's board design.



a. 53°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b. 125°C/W when mounted on a minimum pad of 2 oz copper

- 2. Pulse Test: Pulse Width < 300 $\mu$ s, Duty cycle < 2.0%.
- 3. Starting  $T_J = 25^{\circ}C$ ; N-ch: L = 3mH,  $I_{AS} = 11A$ ,  $V_{DD} = 30V$ ,  $V_{GS} = 10V$

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

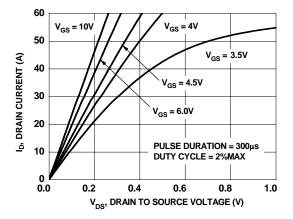


Figure 1. On-Region Characteristics

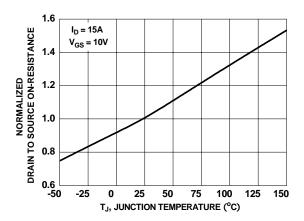


Figure 3. Normalized On-Resistance vs Junction Temperature

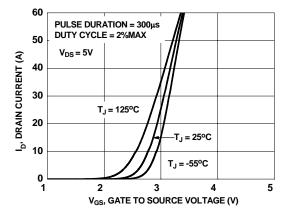


Figure 5. Transfer Characteristics

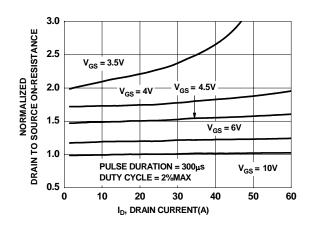


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

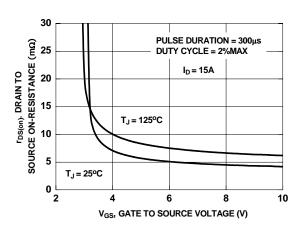


Figure 4. On-Resistance vs Gate to Source Voltage

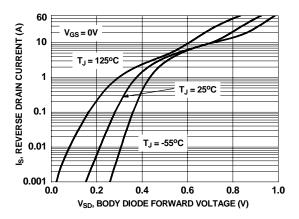


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

## Typical Characteristics T<sub>J</sub> = 25°C unless otherwise noted

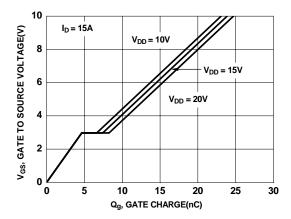


Figure 7. Gate Charge Characteristics

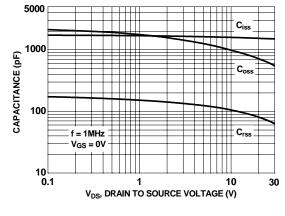


Figure 8. Capacitance vs Drain to Source Voltage

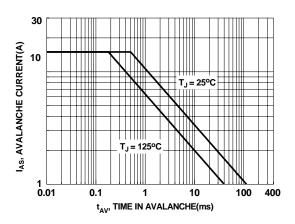


Figure 9. Unclamped Inductive Switching Capability

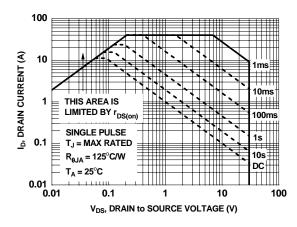


Figure 10. Forward Bias Safe Operating Area

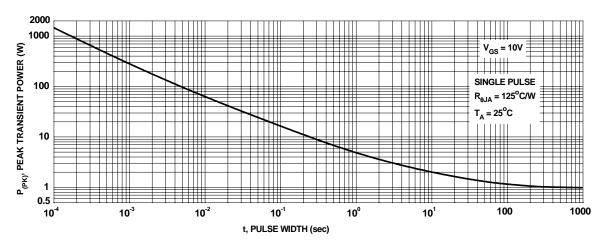


Figure 11. Single Pulse Maximum Power Dissipation

## **Typical Characteristics** T<sub>J</sub> = 25°C unless otherwise noted

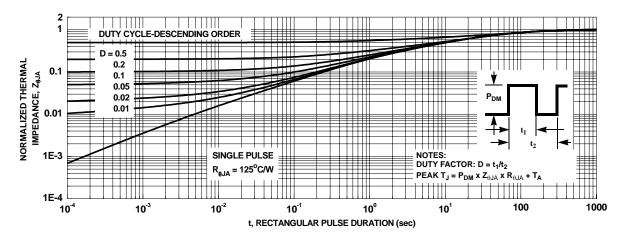


Figure 12. Transient Thermal Response Curve

## Typical Characteristics (continued)

## SyncFET Schottky body diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MoSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverses recovery characteristic of the FDMC8678S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

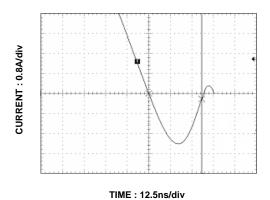


Figure 13. SyncFET body diode reverse recovery characteristic

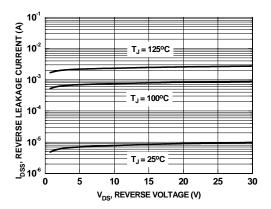
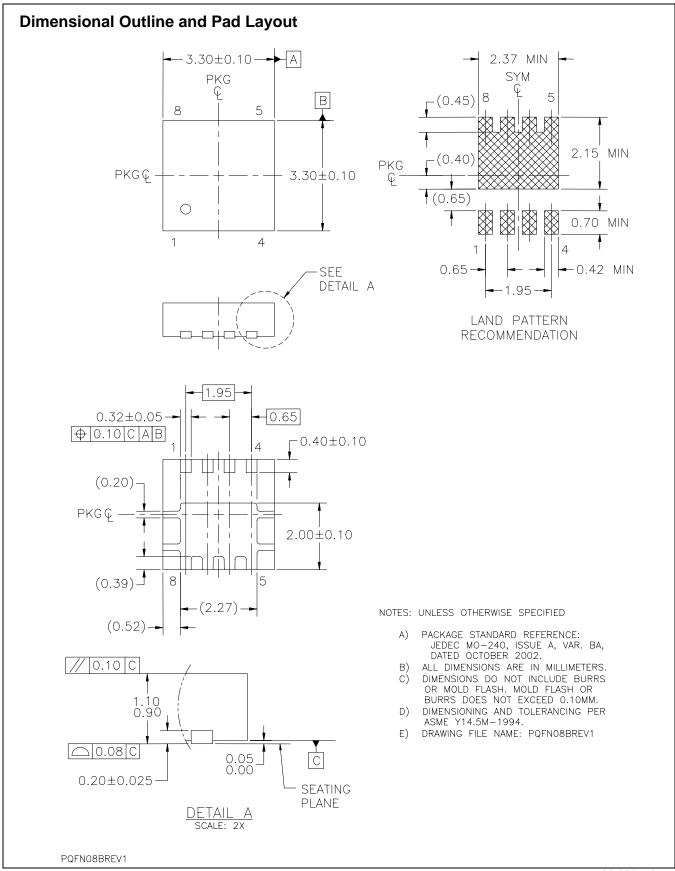


Figure 14. SyncFET body diode reverses leakage versus drain-source voltage





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